

**In the United States Patent and Trademark Office**

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08/884680  
05/27/97

Serial Number:

Appn. Filed:

Applicant(s): **ALEKSANDR L. YUFA**

Appn. Title: **"METHOD AND DEVICE FOR COUNTING AND MEASURING PARTICLES"**

#2  
IDS  
12-897  
R.C.

Examiner:

Group Art Unit:

Mailed: June 27, 1997

At: COLTON, CALIFORNIA

**Information Disclosure Statement**

Assistant Commissioner for Patents  
Washington, District of Columbia 20231

Sir:

Attached is a completed Form PTO-1449 and copies of the pertinent parts of the references listed on this form. The comments on the relevance of any non-English references, pursuant to Rule 98 are contained in the Prior Art section of the specification.

Applied Form-1449 and the Pertinent Parts of the References 19 sheets.

Very respectfully,

  
Signature

ALEKSANDR L. YUFA

Name

June 26, 1997

Date

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P.O. BOX 1677,  
COLTON, CA. 92324

**OTHER PRIOR ART**

(Including Author, Title, Date, Pertinent Pages, Etc.)

- AR** R.G.Knollenberg, B.Schuster--"Detection and Sizing of Small Particles in Open Cavity Gas Laser," Applied Optics, Vo.11, No.7, November 1972, pp.1515-1520;
- AS** R.G.Knollenberg--"An Active Scattering Aerosol Spectrometer," Atmospheric Technology, No.2, June 1973, pp.80-81;
- AR** Schehl, Ergun, Headrick--"Size Spectrometry of Aerosols Using Light Scattering from the Cavity of a Gas Laser," Review of Scientific Instruments, Vol. 44, No.9, September 1973.
- AS** R.G.Knollenberg--"Active Scattering Aerosol Spectrometry," National Bureau of Standards Special Publication, No.412, October 1974, pp.57-64;
- AR** R.G.Knollenberg, R.E.Luehr--"Open Cavity Laser 'Active' Scattering Particle Spectrometry from 0.05 to 5.0 Microns," Fine Particles, Aerosol Generation Measurement, Sampling and Analysis, Academic Press, May 1975, pp.669-696;
- AS** R.G.Knollenberg--"Three New Instruments for Cloud Physics Measurements: The 2-D Spectrometer, the Forward Scattering Spectrometer Probe, and the Active Scattering Aerosol Spectrometer", American Meteorological Society, International Conference on Cloud Physics, July 1976, pp. 554-561;

- AR R.G.Knollenberg --"The Use of Low Power Laser in Particle Size Spectrometry",  
Proceeding of the Society of Photo-Optical Instrumentation Engineers, Practical  
Applications of Low Power Lasers, Vo.92, August 1976, pp.137-152;
- AS Elterman "Brewster Angle Light Trap," Applied Optics, Vol. 16, No. 9, September  
1977.
- AR Marple--"The Aerodynamic Size Calibration of Optical Particle Counters by Inertial  
Impactor," Aerosol Measurment, 1979.
- AS Diehl, Smith, Sydor--"Analysis of Suspended Solids by Single-Particle Scattering,"  
Applied Optics, Vol. 18, No. 10, May 1979.
- AR K.Suda--Review of Scientific Instruments, Vol. 51, No. 8, August 1980, pp.1049-  
1058.
- AS R.G.Knollenberg--"The Measurement of Particle Sizes Below 0.1 Micrometers", Jour-  
nal of Environment Science, January-February, 1985, pp. 64-67.
- AR K.Sasaki, M.Koshioka, H.Misawa, M.Kitamura, H.Masuhara--"Laser-Scanning Mic-  
romanipulation and Spatial Patterning of Fine Particles", Japanese Journal of Applied  
Physics, Vo.30, No.5B, May 1991, pp.L907-L909.
- AS K.Sasaki, M.Koshiok, H.Misawa, M.Kitamura--"Optical Trapping of a Metal Particle  
and a Water Droplet by a Scanning Laser Beam", Applied Physics, Lett.60 (7), Ameri-  
can Institute Physics, February 17, 1992, pp.79-82.

**AR** Peters--"20 Good Reasons to Use In Situ Particle Monitors", Semiconductor International, November 1992, pp.52-57.

**AS** Busselman et al.--"In Situ Particle Monitoring in a Single Wafer Poly Silicon and Silicon Nitride Etch System", IEEE/SEMI, Int'l Semiconductor Manufacturing Science Symposium, 1993, pp.20-26.

	A	B	C	D	E	F	G	H	I
1									
2	Applicant: A.Yufa								page 12
3									
4									
5									
6									
7	Country	From Pat. #	To Pat. #	Class	Subclass	Issue Date	Title		
8									
9									
10									
11	USA	3449567		356/335	378/51	6/10/69			APPARATUS AND PROCESS FOR...
12	AUX		5530551	356/335	356/394	6/25/96			METHOD FOR APPARATUS FOR...
13									
14									
15	USA	3451755		356/336	356/71	6/24/69			PARTICLES SIZE AND DISTRIB. ...
16	JPX		5527714	356/336	436/534	6/18/96			PROCESS FOR DETERMINING...
17									
18									
19	USA	3431424		356/337	250/576	3/04/69			OPTICAL FLUID SAMPLING DEVICE.
20	USA		5510620	356/337	250/339.12	4/23/96			DETECTION OF TURBID OR...
21									
22									
23	USA	3430220		356/338	340/578	2/25/69			FIRE DETECTOR.
24	USA		5530540	356/338	356/246	6/25/96			LIGHT SCATTERING MEASUREM. ...
25									
26									
27	USA	3436152		356/339	250/574	4/01/69			METHOD AND APPARATUS FOR...
28	USA		5515164	356/339	250/576	5/07/96			PARTICLE SENSOR WITH LOW...
29									
30									
31	USA	3450480		356/397	359/373	6/17/69			COMPARISON VIEWER.
32	USA		5510891	356/397	356/30	4/23/96			OBJECT CHARACTERISTIC...

## THE DEPTH OF THE PATENT SEARCH

### THE UNITED STATES OF AMERICA PATENTS



[illegible]











A	B	C	D	E	F	G	H
225							
226	Applicant: A. Yufa						page 19
227							
228	Country	From Pat. #	To Pat. #	Class	Subclass	Issue Date	Title
229							
230	FR	2083052		G01N21/00		1/27/71	PROCÉDÉ ET DISPOSITIF POUR... (METHOD FOR ANALYSIS...)
231							
232	FR		2659448	G01N21/00	G01N31/02	3/08/90	METHODE DE DOSAGE DU... (METHOD FOR DOSING OF...)
233							
234							
235							
236							
237					RUSSIA		
238							
239	SU [RU]	464804		G01N15/02		9/21/71	УСТРОЙСТВО ДЛЯ ОПРЕДЕЛЕНИЯ... (DEVICE FOR THE DETERM. ...)
240							
241	SU [RU]		2027163	G01N15/02		1/20/95	УСТРОЙСТВО ДЛЯ ОПРЕДЕЛЕНИЯ... (DEVICE FOR THE DETERM. ...)
242							
243							
244							
245							
246	SU [RU]	438906		G01N21/00		8/21/72	ГАЗОАНАЛИЗАТОР, (ANALYZER OF THE GAS.)
247							
248	SU [RU]		2031397	G01N21/00		3/20/95	СПОСОБ АНАЛИЗА ВОЛНОВЫХ... (METHOD FOR ANALYSIS OF...)
249							
250							
251							
252					JAPAN		
253							
254	JP			G01N15/01		from 1968 to 1992 yrs	
255		JOURNAL "TOKKE KOHO"					
256	JP			G01N21/00		from 1968 to 1992 yrs	